

GPT-10000 Series

AC/DC/IR/GB Electrical Safety Analyzer



FEATURES

- DC12kV Output and 200VA/500VA AC Test Capacity (500VA short circuit current>200mA)
- 7" TFT LCD
- Comply with IEC 61010-2-034 Design Requirement
- Manual Test Mode/Auto Test Mode
- RMS Current Measurement
- Zero Crossing Turn-on Operation
- Controllable Ramp-up & Ramp-down Time
- Statistics & Analysis Function
- Capacitive Load Testing Capability up to 47µF
- Sweep Function for DUT Characteristic Analysis
- Convenience Listed AUTO Mode Easy to Read Result and Judge
- Internal Storage and USB Storage Available
- Barcode Function Available
- Setting Data Export/Import
- Rear Panel Output Available
- Standard Interface : RS-232C, USB Host/Device and Signal I/O
- Optional Interface : GPIB or LAN
- Universal Power Input



GW Instek introduces the flagship model (high voltage DC 12kV output and 500VA/200VA output capacity) safety analyzer-the GPT-10000 series, which is the first safety analyzer in the world to comply with IEC 61010-2-034 (Safety requirement for electrical requirement for measurement, control and laboratory use – particular requirements for measurement equipment for insulation resistance and test equipment for electric strength), which stipulates that the requirements of the software and hardware interfaces must be followed while designing high voltage and insulation resistance test and measurement instruments so as to ensure that users are provided with necessary protection and warning while using the instruments.

The GPT-10000 series safety analyzer has nine models: GPT-15012 supports DC withstanding test and insulation resistance test; GPT-15004 and GPT-12004 features AC/DC withstanding voltage test, insulation resistance test, AC ground bond test and continuity test; GPT-15003 and GPT-12003 conducts AC/DC withstanding voltage test, insulation resistance test, and continuity test; GPT-15002 and GPT-12002 carry out AC/DC withstanding voltage test and continuity test; GPT-15001 and GPT-12001 executes AC withstanding voltage test and continuity test. The entire series utilizes a high-efficient PWM amplifier to effectively exclude the influence from the fluctuating input voltage or distorted waveforms so as to guarantee a stable high-voltage output while conducting AC withstanding voltage test on the DUT to meet the safety regulations such as IEC, EN, UL, CSA, GB, JIS that demand the test requirements for various electronic/electrical products or parts.

To comply with IEC 61010-2-034 requirements, the series takes into account of safety by adopting the double insulation design for input power supply and output voltage to enhance user safety. Additionally, the retracted on-off switch design (START key) and various (optional) mechanisms for test activation (for instance, press and hold for 1 second to activate, activation by pressing double keys, etc.) are incorporated into the series to avoid accidentally touching that results in high voltage/large current output causing damage and danger to products or users. High illumination LED lights (flashing or permanently lit) and a high volume audial indicator are included in designing the series to provide warnings of the status of the on-going tests or judgement results from the safety analyzer. On top of that, the DUT will be automatically discharged to the safe voltage (approximately 30V) after each test to prevent large residual test voltage from causing harm to users.

The series utilizes 7-inch color TFT LCD and inherits the consistent simplicity key design style of the product family to allow users to experience easy operations and a clear observation of the test results. Among the series, GPT-15012 supports high DC withstanding voltage test up to DC 12kV, and the major test functions of other models include AC withstanding voltage test (AC 5kV), DC withstanding voltage test (DC 6kV), insulation resistance test (DC 50V~5000V), ground bond test (AC 32A), and grounding continuity test (DC 100mA fixed). The series also collocates with superb output adjustment resolution, measurement resolution (AC withstanding voltage: 1 μ A; DC withstanding voltage: 0.1 μ A; insulation resistance: 0.1MΩ; ground bond: 0.1MΩ; continuity test: 0.01Ω), controllable voltage ramp up and ramp down time settings, and upper/lower limit judgement settings, and large capacitance test capability (up to 47uF) for DUT with large capacitance such as surge absorber and large capacitance on the input terminal of EMC/EMI prevention. For Insulation resistance, provides 10mA pre-charged current (fixed) to first rapidly fully charge the DUT's capacitive load and then to conduct test and measurement so as to avoid misjudgment from fluctuating inrush current. All the above features of the series facilitate a more flexible execution of the required tests so that users can obtain accurate test and measurement results.

The statistic function is the highlight of the series. Test items, number of tests, judgement results are recoded after testing and the test results can be shown by bar graph on the display. Users can immediately learn the status of product tests and judgement distribution during the manufacturing process without using a PC. The other strong feature is the sweep function, which can be used for the analysis on product's crash point. Users can use the sweep mode to see the curve diagram of the test results after finishing the functional tests. Users can also select any time point during the process to analyze the relation between voltage and current (when ACW or DCW is selected). The test result of the certain period of time can be swept by setting start and stop time points to analyze the relation between voltage and current under that time frame. Furthermore, the tabular continuity test function can combine 10 manual memory sets to carry out automatic tests or 9 manual memory sets with one connection device to connect next automatic test so as to increase the test items of the continuity test. Users can obtain various test values and judgement results without switching to a different display screen.

Other functions and features of the GPT-10000 series include 100 sets of manual test as well as 100 sets of auto test memory for the storage of different test conditions and the saved test conditions can be exported to another GPT-10000 through USB flash drive to quick replication and expansion of production line equipment; barcode scanner can be conducted to the front panel USB host of GPT10000 for managing test condition of DUT and then be able to quick and correctly recall required test condition; rear output terminal for system integration; front panel remote control terminal mount/rear panel Signal I/O for users to conveniently control the analyzer's output/stop based upon the requirements. The USB storage function allows test results to be stored in the USB flash drive or internal memory to save the trouble of using a PC, and the function is conducive to the follow-up data analysis. For users with the requirements of PC control and test results recording, the series also provides RS-232C, USB and option GPIB or LAN.ts of PC control and test results recording, the series also provides RS-232C, USB and option GPIB or LAN.



Providing the markets with safe electronic products is the responsibility of every manufacturer! Similarly, safety analyzer that tests whether electronic products meet safety regulations must attach the importance to the safety it provides! GPT-10000 Series is the world's first safety analyzer to comply with IEC 61010-2-034 (Safety requirement for electrical requirement for measurement, control and laboratory use – particular requirements for

measurement equipment for insulation resistance and test equipment for electric strength). Apart from this, the safety considerations also include double insulation for input and output voltages, safe output/warning mechanism, post-test discharge mechanism, etc. to ensure user safety during the operation.

B. HIGH ACCURACY AND HIGH RESOLUTION TESTING PERFORMANCE



High Adjustment & Measurement Resolution

For production tests and characteristic verification, the GPT-10000 Series provides a withstand voltage test voltage (AC 5kV/DC 6kV) that can be adjusted in 1V steps with current measurement resolutions up to 1 μ A (ACW) or 0.1 μ A (DCW) to realize the small leakage current measurement for products or components. In addition, the insulation resistance test voltage can be adjusted in 50V steps from a DC output range of 50V to 5000V, and the resistance measurement resolution can reach 0.1M Ω . Since most safety regulations require AC power supply for ground bond test, the

GPT-10000 Series provides 8Vac (open) and 3A to 32Aac current for ground bond test with a resistance measurement resolution of $0.1m\Omega$. The entire series provides the continuity grounding test function with a 100mAdc (fixed) test source and a measurement resolution of 0.01Ω to detect if the tested equipment is correctly grounded. With these functions, users can perform various safety tests and verifications with high accuracy and reliability.

FLEXIBLE SUPPLEMENTARY TESTING MECHANISM



Testing Period Timing

To make tests compliant with the test requirements of relevant safety regulations, the GPT-10000 Series provides a more flexible output sequence setting starting from the start point of the test. Taking the AC/DC withstand voltage test as an example, the initial voltage can be set. Users determine the initial voltage ratio (i.e., the ratio of the rated test voltage), and then the voltage ramp up can also be set to reduce the risk of insulation breakdown or damage to the DUT caused by transient high voltages. After the rated test voltage is reached, the upper/lower limit judgement window, delay judgment and test timer mechanism can be set to assist users to conduct tests smoothly and correctly. The new voltage ramp down time setting allows users to test with a ramp down voltage to

avoid the impact of excessively high rated test voltage to instantaneous discharge on the DUT.

With respect to the insulation resistance test, other than the newly added grounding mode to perform test in accordance with the actual grounding state of the DUT, the setting mechanism of the supplementary upper/lower limit judgement is also added to shorten the test time. The user-definable mode mechanisms include: STOP ON FAIL: The test is terminated as soon as the FAIL setting is met; STOP ON PASS: The test is terminated as long as the PASS setting is met, or TIMER: judgement is conducted when the timer time is reached.



Statistic



Analysis

The GPT-10000 Series provides the statistic function, which can record the test functions and judgment results in the temporary storage area (60,000 lots max.). Users can immediately learn the test of each function during the test without using a PC. The distribution of the good products can be analyzed to understand the quality of the batch based on the data. If most

of them fall at the critical point that is close to be categorized as defect product, the results can be found in the test process in time so as to improve the manufacturing process and stop the defect products from entering the markets to ensure the reliability of products after leaving the factory.

SWEEP AND TABULAR AUTOMATIC TEST



The values of point by cursor

Sweep Function

The GPT-10000 Series features a unique sweep function, which displays a curve diagram of the test results of the DUT. Test readings are recorded point by point based on the applied test voltage or current and relevant settings (such as initial voltage, ramp up time, test time, or ramp down time). After the test is completed, users can learn the amount of applied energy (voltage or current) at a specific time point and the results of measurement parameters by moving the cursor position so as to help users understand the changes of the measurement parameters (current or resistance) during the test. The function can also be used to determine the



Tabular Automatic Test

critical break down of the DUT. With respect to the automatic test function, each automatic test has up to 10 manual test items and all related settings and result judgement are presented in a table, so that users can easily obtain the results of all test items at a time. Other than that, if there are multiple automatic test connection requirements, uses only need to select CON in the last item of the table to automatically connect the automatic measurement of the next position (such as AUTO-012 ~ AUTO-013)

BARCODE FUNCTION



GPT-10000 Series supports the connection mechanism of the barcode machine. Users can manage the test conditions of each DUT through the use and setting of the barcode machine, which is especially suitable for mixed-type production lines. By scanning the barcode of the DUT, GPT- 10000 Series can automatically reveal the corresponding test conditions, which can avoid using wrong conditions and causing damage to the DUT.

G. SETTING DATA EXPORT / IMPORT MECHANISM



Setting Data Export / Import

In order to expedite the deployment of the production line and achieve the consistency of test conditions, GPT-10000 Series provides a mechanism that can replicate test conditions. Users only need to set test conditions

for one unit, and all settings can be copied via a USB flash drive. Other than the rapid setting of consistent test conditions, it can also avoid the difference while conducting settings.

H. COMPLETE TEST DATA RETRIEVAL INTERFACE



Storage Function

In order to facilitate users to analyze the results of the safety test, GPT-10000 Series provides the USB storage function in addition to its own statistic and analysis functions. When a USB is inserted and the storage function is activated, each time the test button (START) is pressed, the test results of all tests (every manual or automatic test item) are automatically saved to the USB in the form of a text file (txt) for follow-up analysis. When there is no USB flash drive available, users can turn on the internal memory storage function (up to 30,000 lots) to store the results of each test in the internal memory first, and then transfer them to an external device via a USB flash drive when available. Besides, the entire series is equipped with RS-232C and USB device (GPIB or LAN is optional) for easy retrieval of test data and results by connecting a PC.

I. USER DEFINED SIGNAL I/O



SIGNAL IO Selection for AUTO Test (blue zone)

Self-defined Signal I/O

For interface connections, the GPT-10000 Series offers external control or a variety of remotely connected ports such as a signal I/O port that can be used to connect an external controller or PLC. The signal I/O's output signal pins can be self-defined so as to collocate with various PLC control requirements.

PANEL INTRODUCTION

GPT-15012



GPT-15004/12004



GPT-15001/15002/15003/12001/12002/12003



- 1. Start & Stop Button
- 2. Function Selection Key
- 3. 7" LCD Display
- 4. Navigator Key
- 5. Status Indicator (PASS/FAIL)
- 6. Wheel & Test Mode key
- 7. USB Host

- 8. REMOTE Terminal
- 9. Hi-Voltage Output Terminal & Indicator
- 10. Current Output Terminal & Return
- 11. Rear Output Terminal & Indicator
- 12. Series Port (RS-232C/USB device)
- 13. Signal I/O
- 14. GPIB or LAN (optional)

SELECTION GUIDE

Function Model	Output Capacity	AC	DC	IR	GB	Continuity	Rear Output
GPT-15012	12kVdc		\checkmark	1			\checkmark
GPT-15001	500VA	\checkmark				\checkmark	\checkmark
GPT-15002	500VA	\checkmark	\checkmark			1	\checkmark
GPT-15003	500VA	\checkmark	\checkmark	\checkmark		1	\checkmark
GPT-15004	500VA	\checkmark	\checkmark	\checkmark	\checkmark	1	\checkmark
GPT-12001	200VA	\checkmark				\checkmark	\checkmark
GPT-12002	200VA	\checkmark	\checkmark			1	\checkmark
GPT-12003	200VA	\checkmark	\checkmark	\checkmark		1	\checkmark
GPT-12004	200VA	\checkmark	\checkmark	\checkmark	\checkmark	\checkmark	\checkmark

APPLICATIONS

- Safety Testing of Electrical Product in Manufacturing
 Power Cord
 Home Appliances
 Information Technology Equipment
 Medical Equipment
 Household and Similar Electrical Appliances
 Luminaires
 Audio, Video and Similar Electronic Apparatus
- Quality Assurance Verification
- Safety Standard Compliance Pre-qualification in R&D

Note : GPT-15000 Series ACW short current > 200mA



GPIB

USB

Signal I/O

Rear Output

0

LAN

USB Host

RS-232

CE

0



SPECIFICATIONS			
MODEL	GPT-15012	GPT-15000 Series	GPT-12000 Series
AC WITHSTANDING Output-Voltage Range			
Output-Voltage Resolution		0.050kV~5.000kV 1V	0.050kV~5.000kV 1V
Output-Voltage Accuracy		±(1% of setting + 5V) [no load]	±(1% of setting + 5V) [no load]
Maximum Rated Load Maximum Rated Current		500 VA (5kV/100mA) 100mA (0.5kV <v≦5kv);10ma (0.05kv≦v≦0.5kv)<="" th=""><th>200 VA (5kV/40mA) 40mA (0.5kV<v≦5kv);10ma (0.05kv≦v≦0.5kv)<="" th=""></v≦5kv);10ma></th></v≦5kv);10ma>	200 VA (5kV/40mA) 40mA (0.5kV <v≦5kv);10ma (0.05kv≦v≦0.5kv)<="" th=""></v≦5kv);10ma>
Output-Voltage Waveform		Sine wave	Sine wave
Output-Voltage Frequency		50 Hz / 60 Hz selectable	50 Hz / 60 Hz selectable
Voltage Regulation		±(1% + 5V) [maximum rated load no load] ±(1% of reading + 5V)	$\pm(1\% + 5V)$ [maximum rated load no load] $\pm(1\%$ of reading + 5V)
Voltmeter Accuracy Current Measurement Range	_	1µA~100.0mA	1μΑ~40.00mA
Current Best Resolution		1μΑ / 10μΑ / 100μΑ	1μΑ / 10μΑ
Current Measurement Accuracy		$\pm(1.5\% \text{ of reading} + 30\mu\text{A})$	±(1.5% of reading + 30μA)
Current Offset Window Comparator Method		60μΑ Maximum Yes	60μA Maximum Yes
ARC Detect		Yes	Yes
RAMP UP (Rise Time)		0.1s~999.9s	0.1s~999.9s
RAMP DOWN (Fall Time) TIMER (Test Time)*		0.0s~999.9s OFF, 0.3s~999.9s	0.0s~999.9s OFF, 0.3s~999.9s
WAIT TIME		0.0s~999.9s	0.0s~999.9s
GND		ON/OFF	ON/OFF
DC WITHSTANDING			
Output-Voltage Range Output-Voltage Resolution	0.050kV~12.00kV 1V	0.050kV~6.000kV	0.050kV~6.000kV 1V
Output-Voltage Accuracy	±(1% of setting + 5V) [no load]	±(1% of setting + 5V) [no load]	±(1% of setting + 5V) [no load]
Maximum Rated Load	120W (12kV/10mA)	100W (5kV/20mA)	50W (5kV/10mA)
Maximum Rated Current	10mA (0.5kV< V ≦12kV); 2mA (0.05kV≦ V ≦0.5kV)	20mA (0.5kV< V \leq 6kV); 2mA (0.05kV \leq V \leq 0.5kV)	10mA (0.5kV< V ≦6kV); 2mA (0.05kV≦ V ≦0.5kV)
Voltage Regulation	±(1% + 5V) [maximum rated load no load]	±(1% + 5V) [maximum rated load no load]	±(1% + 5V) [maximum rated load no load]
Voltmeter Accuracy	$\pm (1\% \text{ of reading} + 5V)$	\pm (1% of reading + 5V)	$\pm (1\% \text{ of reading} + 5V)$
Current Measurement Range Current Best Resolution	1μΑ~10.00mΑ 0.1μΑ /1μΑ /10μΑ	1μΑ~20.00mΑ 0.1μΑ /1μΑ /10μΑ	1μΑ~10.00mΑ 0.1μΑ /1μΑ /10μΑ
Current Measurement Accuracy	$\pm(1.5\% \text{ of reading} + 3\mu\text{A}) \text{ when I Reading} <1\text{ mA};$	$\pm(1.5\% \text{ of reading} + 3\mu\text{A}) \text{ when I Reading} <1\text{mA};$	$\pm (1.5\% \text{ of reading} + 3\mu\text{A}) \text{ when I Reading} < 1\text{mA};$
	\pm (1.5% of reading + 30µA) when I Reading 1mA	±(1.5% of reading + 30µÅ) when I Reading≧1mÅ	±(1.5% of reading + 30µA) when I Reading≥1mA
Current Offset Window Comparator Method	5µA Maximum	5μA Maximum Yes	5μA Maximum Yes
ARC Detect	Yes Yes	Yes	Yes
RAMP UP (Rise Time)	0.1s~999.9s	0.1s~999.9s	0.1s~999.9s
RAMP DOWN (Fall Time)	0.0s~999.9s OFF, 0.3s~999.9s	0.0s~999.9s OFF, 0.3s~999.9s	0.0s~999.9s OFF, 0.3s~999.9s
TIMER (Test Time)* WAIT TIME	0.0s~999.9s	0.0s~999.9s	0.0s~999.9s
GND	ON/OFF	ON/OFF	ON/OFF
INSULATION RESISTANCE	(Firmware version: V.1.06 or later)	(Firmware version: V.1.06 or later)	(Firmware version: V.1.12 or later)
Output Voltage Output-Voltage Resolution	50V~5000V dc 50V	50V~5000V dc 50V	50V~5000V dc 50V
Output-Voltage Accuracy	±(1% of setting + 5V) [no load]	±(1% of setting + 5V) [no load]	±(1% of setting + 5V) [no load]
Resistance Measurement Test Voltage Display Range	Massurement Panga / Assurage	Mangurament Range / Accuracy	
.,	Measurement Range / Accuracy	Measurement Range / Accuracy	
50V≦V≦100V 0.001MΩ~10.00GΩ	0.1MΩ~1MΩ:±(5% of reading+3count); 1.1MΩ~50MΩ:±(5% of reading+1count);	0.1MΩ~1MΩ:±(5% of reading+3count); 1.1MΩ~50MΩ:±(5% of reading+1count);	$0.1M\Omega \sim 1M\Omega: \pm (5\% \text{ of reading}+3 \text{ count});$ $1.1M\Omega \sim 50M\Omega: \pm (5\% \text{ of reading}+1 \text{ count});$
150V≦V≦450V 0.001MΩ~20.00GΩ	$50.1M\Omega \sim 2G\Omega: \pm (10\% \text{ of reading}+1 \text{ count})$	$50.1M\Omega \sim 2G\Omega: \pm (10\% \text{ of reading}+1 \text{ count}),$	$50.1M\Omega \sim 2G\Omega:\pm(10\% \text{ of reading}+1 \text{ count})$
500V≦V≦1200V 0.001MΩ~50.00GΩ	$0.1M\Omega \sim 1M\Omega: \pm (5\% \text{ of reading} + 3 \text{ count});$	0.1MΩ~1MΩ:±(5% of reading+3count);	0.1MΩ~1MΩ:±(5% of reading+3count);
	$1.1M\Omega \sim 500M\Omega: \pm (5\% \text{ of reading} + 1 \text{ count});$	1.1MΩ~500MΩ:±(5% of reading+1count);	1.1MΩ~500MΩ:±(5% of reading+1count);
	500.1MΩ~9.999GΩ:±(10% of reading+1count);	500.1MΩ~9.999GΩ:±(10% of reading+1count);	500.1MΩ~9.999GΩ:±(10% of reading+1count);
	$10G\Omega \sim 50G\Omega: \pm (20\% \text{ of reading} + 1 \text{ count})$	$10G\Omega \sim 50G\Omega: \pm (20\% \text{ of reading} + 1 \text{ count})$	$10G\Omega \sim 50G\Omega$:±(20% of reading+1count)
1250V≦V≦5000V 0.001MΩ~50.00GΩ	$0.1M\Omega \sim 1M\Omega: \pm (5\% \text{ of reading} + 3\text{ count});$	$0.1M\Omega \sim 1M\Omega: \pm (5\% \text{ of reading + 3 count});$	$0.1M\Omega \sim 1M\Omega: \pm (5\% \text{ of reading + 3 count});$
	1.1MΩ~500MΩ:±(5% of reading+1count); 500.1MΩ~9.999GΩ:±(10% of reading+1count);	1.1MΩ~500MΩ:±(5% of reading+1count); 500.1MΩ~9.999GΩ:±(10% of reading+1count);	1.1MΩ~500MΩ:±(5% of reading+1count); 500.1MΩ~9.999GΩ:±(10% of reading+1count);
	$10G\Omega \sim 50G\Omega: \pm (15\% \text{ of reading} + 100 \text{ count})$	$10G\Omega \sim 50G\Omega: \pm (15\% \text{ of reading}+1 \text{ count}),$	$10G\Omega \sim 50G\Omega: \pm (15\% \text{ of reading} + 100 \text{ count})$
Voltage Regulation	±(1% + 5V) [maximum rated load no load]	±(1% + 5V) [maximum rated load no load]	±(1% + 5V) [maximum rated load no load]
Voltmeter Accuracy	±(1% of reading + 5V)	±(1% of reading + 5V)	±(1% of reading + 5V)
Short-Circuit Current Output Impedance	10mA max. 2kΩ	10mA max. 2kΩ	10mA max. 2kΩ
Window Comparator Method	ZkΩ Yes	Yes	Yes
RAMP UP (Rise Time)	0.1s~999.9s	0.1s~999.9s	0.1s~999.9s
RAMP DOWN (Fall Time) TIMER (Test Time)*	0.0s~999.9s 0.3s~999.9s	0.0s~999.9s 0.3s~999.9s	0.0s~999.9s 0.3s~999.9s
WAIT TÌME Í	0.0s~999.9s	0.0s~999.9s	0.0s~999.9s
GND	ON/OFF	ON/OFF	ON/OFF
GROUND BOND		02.004.22.004	03.004 .32.004
Output-Current Output-Current Resolution		03.00A~32.00A ac 0.01A	03.00A~32.00A ac 0.01A
Output-Current Accuracy		$3A \le 1 \le 8A: \pm (1\% \text{ of reading} + 0.2A);$	$3A \le 1 \le 8A:\pm(1\% \text{ of reading}+0.2A);$
		$8A < I \le 32A: \pm (1\% \text{ of reading} + 0.05A)$	$8A < I \leq 32A: \pm (1\% \text{ of reading} + 0.05A)$
Test-Voltage		8Vac max (open circuit) 50Hz/60Hz selectable	8Vac max (open circuit) 50Hz/60Hz selectable
Test-Voltage Frequency			
Test-Voltage Frequency Ohmmeter Measurement Range	_	$1m\Omega \sim 650m\Omega$	1mΩ~ 650mΩ
Ohmmeter Measurement Range Ohmmeter Measurement Resolution	-	1mΩ~ 650mΩ 0.1mΩ	0.1mΩ
Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Accuracy	-	$1 \text{ m} \Omega \sim 650 \text{ m} \Omega$ 0.1 m Ω ±(1% of reading + 2 m Ω)	0.1mΩ ±(1% of reading + 2 mΩ)
Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Accuracy Window Comparator Method	_	1mΩ~ 650mΩ 0.1mΩ	0.1mΩ
Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Accuracy Window Comparator Method TIMER (Test Time)* Test Method	_	$1 \text{ m} \Omega^{-} 650 \text{ m} \Omega$ $0.1 \text{ m} \Omega$ $\pm (1\% \text{ of reading} + 2 \text{ m} \Omega)$ Yes 0.3 s - 999.9 s Four Terminal	0.1mΩ ±(1% of reading + 2 mΩ) Yes 0.3s-999.9s Four Terminal
Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Accuracy Window Comparator Method TIMER (Test Time)* Test Method GND	_	1mΩ ² - 650mΩ 0.1mΩ ±(1% of reading + 2 mΩ) Yes 0.3s~999.9s	0.1mΩ ±(1% of reading + 2 mΩ) Yes 0.3s~999.9s
Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Accuracy Window Comparator Method TIMER (Test Time)* Test Method GND CONTINUITY TEST	_	1mΩ ² - 650mΩ 0.1mΩ ±(1% of reading + 2 mΩ) Yes 0.3s~999.9s Four Terminal ON/OFF	0.1mΩ ±(1% of reading + 2 mΩ) Yes 0.3s~999.9s Four Terminal ON/OFF
Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Accuracy Window Comparator Method TIMER (Test Time)* Test Method GND	_	$1 \text{ m} \Omega^{-} 650 \text{ m} \Omega$ $0.1 \text{ m} \Omega$ $\pm (1\% \text{ of reading} + 2 \text{ m} \Omega)$ Yes 0.3 s - 999.9 s Four Terminal	0.1mΩ ±(1% of reading + 2 mΩ) Yes 0.3s-999.9s Four Terminal
Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Accuracy Window Comparator Method TIMER (Test Time)* Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Range	_	1 mΩ ² - 650mΩ 0.1mΩ ±(1% of reading + 2 mΩ) Yes 0.3s~999.9s Four Terminal ON/OFF 100mA dc (fixed) 0.10Ω~ 70.00Ω 0.01Ω	0.1mΩ ±(1% of reading + 2 mΩ) Yes 0.3s-999.9s Four Terminal ON/OFF 100mA dc (fixed) 0.10Ω~ 70.00Ω 0.01Ω
Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Accuracy Window Comparator Method TIMER (Test Time)* Test Method CND CONTINUITY TEST Output-Current Ohmmeter Measurement Range	_	$ 1 m \Omega^{-} 650 m \Omega 0.1 m \Omega \pm (1% of reading + 2 m \Omega) Yes 0.3s-999.9s Four Terminal ON/OFF 100mA dc (fixed) 0.10 \Omega ~ 70.00 \Omega $	0.1mΩ ±(1% of reading + 2 mΩ) Yes 0.3s~999.9s Four Terminal ON/OFF 100mA dc (fixed) 0.10Ω~ 70.00Ω

MODEL	GPT-15012	GPT-15000 Series	GPT-12000 Series		
MEMORY					
Single Step Memory Automatic Testing Memory	MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10	MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10	MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10		
INTERFACE		· · · · · · · · · · · · · · · · · · ·	· · ·		
Standard (Front) Standard (Rear) Option	REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, GPIB, LAN	REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, GPIB, LAN	REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, GPIB, LAN		
DISPLAY					
	7" color LCD	7" color LCD	7" color LCD		
POWER SOURCE		÷			
	AC 100V~240V ± 10%, 50Hz/60Hz; Power consumption : Max. 400VA	AC 100V~240V ± 10%, 50Hz/60Hz; Power consumption : Max. 1000VA	AC 100V~240V ± 10%, 50Hz/60Hz; Power consumption : Max. 400VA		
DIMENSIONS & WEIGHT					
	GPT-15012:380(W)x148(H)x492(D)mm; Approx. 9.8kg(max.)	GPT-15001/15002/15003:380(W)x148(H) x492(D)mm; Approx.17kg(max.); GPT-15004:380(W)x148(H)x546(D)mm; Approx.21kg	GPT-12001/12002/12003:380(W)x148(H) x 436(D) mm; Approx. 11kg (max.); GPT-12004 : 380(W)x148(H)x454(D)mm; Approx. 15kg		
Note : * TIMER Accuracy: +/-(100ppn	n+20ms)	Specifications subject	ct to change without notice. GPT-10000CD3		
ORDERING INFORM	ATION	ACCESSORIES			
		Power cord x 1, Interlock Key x 1, Remote Terminal, Cable GHT-119 x 1,			

GPT-15012	DC 12kV DC/IR Electrical Safety Analyzer
GPT-15004	AC/DC/IR/GB Electrical Safety Analyzer
GPT-15003	AC/DC/IR Electrical Safety Analyzer
GPT-15002	AC/DC Electrical Safety Analyzer
GPT-15001	AC Electrical Safety Analyzer
GPT-12004	AC/DC/IR/GB Electrical Safety Analyzer
GPT-12003	AC/DC/IR Electrical Safety Analyzer
GPT-12002	AC/DC Electrical Safety Analyzer
GPT-12001	AC Electrical Safety Analyzer

	Specifications subject to change without notice. GFT	-10000CD3BI		
ACCESS	SORIES			
Power cord x 1, Interlock Key x 1, Remote Terminal, Cable GHT-119 x 1, Test lead GHT-115 x 1 for GPT-15001/15002/15003/12001/12002/12003, Test lead GHT-115 x 1, GTL-215 x 1 for GPT-15004/12004, Test lead GHT-120 x 1 for GPT-15012				
OPTION	N			
GPT-10K	(G1 GPIB card GPT-10KL1 LAN card			
OPTIONAL ASSESSORIES				
GHT-118 GHT-113 GHT-205	//GHT-117(EU) High Voltage Adapter Box //GHT-118(EU) High Voltage/Ground Bond Adapter Box i High Voltage Test Pistol GTL-264 i High Voltage Test Pistol Signal I/O Conve i High Voltage Test Pistol Signal I/O Conve i High Voltage Test Pistol Signal I/O Conve i High Voltage Test Pistol Approx. 200mm null Modem for Computer GRA-440 Rack Adapter Par	pin Female.		
	USB Cable, A-B type, approx. 1.2m GPIB Cable, approx. 2m	iei (19,40)		

ASSESSORIES GUIDE

Model Assessories	GPT-15012	GPT-15000 Series	GPT-12000 Series
GHT-117/ GHT-117(EU)	-	✓	✓
GHT-118/ GHT-118(EU)	-	\checkmark	\checkmark
GHT-113	-	\checkmark	\checkmark
GHT-205	-	\checkmark	\checkmark
GTL-232	\checkmark	\checkmark	\checkmark
GTL-246	\checkmark	\checkmark	\checkmark
GTL-248	\checkmark	\checkmark	\checkmark
GTL-264	\checkmark	\checkmark	\checkmark
GRA-440	\checkmark	\checkmark	\checkmark
GPT-10KG1	\checkmark	\checkmark	\checkmark
GPT-10KL1	\checkmark	\checkmark	\checkmark



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